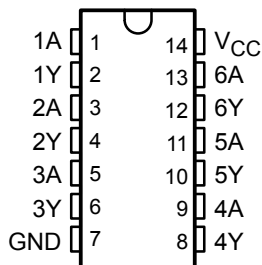
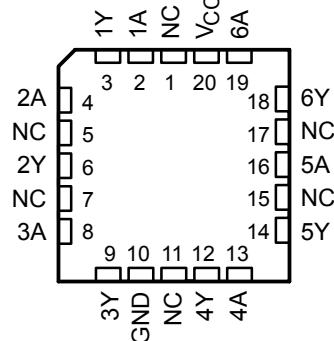


- Wide Operating Voltage Range of 2 V to 6 V
- Outputs Can Drive Up To 10 LSTTL Loads
- Low Power Consumption, 20- $\mu$ A Max  $I_{CC}$
- Typical  $t_{pd} = 8$  ns
- $\pm 4$ -mA Output Drive at 5 V
- Low Input Current of 1  $\mu$ A Max

SN54HC04 . . . J OR W PACKAGE  
SN74HC04 . . . D, N, NS, OR PW PACKAGE  
(TOP VIEW)



SN54HC04 . . . FK PACKAGE  
(TOP VIEW)



NC – No internal connection

## description/ordering information

The 'HC04 devices contain six independent inverters. They perform the Boolean function  $Y = \bar{A}$  in positive logic.

## ORDERING INFORMATION

T <sub>A</sub>	PACKAGE†		ORDERABLE PART NUMBER	TOP-SIDE MARKING
–40°C to 85°C	PDIP – N	Tube of 25	SN74HC04N	SN74HC04N
	SOIC – D	Tube of 50	SN74HC04D	HC04
		Reel of 2500	SN74HC04DR	
		Reel of 250	SN74HC04DT	
	SOP – NS	Reel of 2000	SN74HC04NSR	HC04
	TSSOP – PW	Tube of 90	SN74HC04PW	HC04
		Reel of 2000	SN74HC04PWR	
Reel of 250		SN74HC04PWT		
–55°C to 125°C	CDIP – J	Tube of 25	SNJ54HC04J	SNJ54HC04J
	CFP – W	Tube of 150	SNJ54HC04W	SNJ54HC04W
	LCCC – FK	Tube of 55	SNJ54HC04FK	SNJ54HC04FK

† Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at [www.ti.com/sc/package](http://www.ti.com/sc/package).

FUNCTION TABLE  
(each inverter)

INPUT A	OUTPUT Y
H	L
L	H



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS  
INSTRUMENTS**

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On products compliant to MIL-PRF-38535, all parameters are tested unless otherwise noted. On all other products, production processing does not necessarily include testing of all parameters.